

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/782,523 | | Applicant(s)/Patent Under Reexamination EHRICH ET AL. | |
| | Examiner Kuen S. Lu | | Art Unit 2167 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-2005/0097190 | 05-2005 | Abdelhak, Aaron | 709/217 |
| * | B | US-2005/0198300 | 09-2005 | Gong et al. | 709/227 |
| * | C | US-2004/0148351 | 07-2004 | Cotte, Pierre-Alain | 709/205 |
| * | D | US-2003/0154277 | 08-2003 | Haddad et al. | 709/224 |
| * | E | US-2003/0053420 | 03-2003 | Duckett et al. | 370/252 |
| * | F | US-2003/0120472 | 06-2003 | Lind, Jeffrey D. | 703/13 |
| * | G | US-7,027,997 | 04-2006 | Robinson et al. | 705/9 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.